

Notice of References Cited		Application/Control No. 10/581,322	Applicant(s)/Patent Under Reexamination FUKUI ET AL.	
		Examiner SUN JAE Y. LOEWE	Art Unit 1626	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,470,807	12-2008	Shoda et al.	560/56
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Newman et al., DDT Vol 8, October 2003, pg. 898-90
	V	Chawla et al., CRIPS Vol 5, No 1, January - March 2004, pg. 9-12
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.